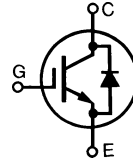


# High Speed IGBT with Diode

**IXSH 30N60BD1**  
**IXSK 30N60BD1**  
**IXST 30N60BD1**

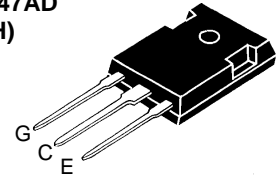
**V<sub>CES</sub> = 600 V**  
**I<sub>C25</sub> = 55 A**  
**V<sub>CE(sat)</sub> = 2.0 V**  
**t<sub>fi</sub> = 140 ns**

## Short Circuit SOA Capability

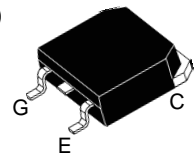


Symbol	Test Conditions	Maximum Ratings	
V <sub>CES</sub>	T <sub>J</sub> = 25°C to 150°C	600	V
V <sub>CGR</sub>	T <sub>J</sub> = 25°C to 150°C; R <sub>GE</sub> = 1 MΩ	600	V
V <sub>GES</sub>	Continuous	±20	V
V <sub>GEM</sub>	Transient	±30	V
I <sub>C25</sub>	T <sub>C</sub> = 25°C	55	A
I <sub>C90</sub>	T <sub>C</sub> = 90°C	30	A
I <sub>CM</sub>	T <sub>C</sub> = 25°C, 1 ms	110	A
<b>SSOA (RBSOA)</b>	V <sub>GE</sub> = 15 V, T <sub>J</sub> = 125°C, R <sub>G</sub> = 10 Ω Clamped inductive load, V <sub>CL</sub> = 0.8 V <sub>CES</sub>	I <sub>CM</sub> = 60	A
<b>t<sub>SC</sub> (SCSOA)</b>	V <sub>GE</sub> = 15 V, V <sub>CE</sub> = 360 V, T <sub>J</sub> = 125°C R <sub>G</sub> = 33 Ω, non repetitive	10	μs
P <sub>C</sub>	T <sub>C</sub> = 25°C	200	W
T <sub>J</sub>		-55 ... +150	°C
T <sub>JM</sub>		150	°C
T <sub>stg</sub>		-55 ... +150	°C
M <sub>d</sub>	Mounting torque	1.13/10	Nm/lb.in.
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	°C
<b>Weight</b>	TO-247/TO-268	6/4	g
	TO-264	10	g

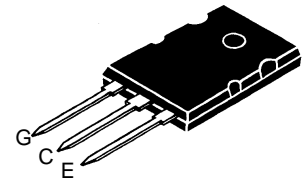
**TO-247AD (IXSH)**



**TO-268 (D3) (IXST)**



**TO-264 (IXSK)**



G = Gate                      C = Collector  
E = Emitter                    TAB = Collector

### Features

- International standard packages: JEDEC TO-247, TO-264 & TO-268
- Short Circuit SOA capability
- Medium frequency IGBT and anti-parallel FRED in one package
- New generation HDMOS™ process

### Applications

- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switch-mode and resonant-mode power supplies

### Advantages

- Space savings (two devices in one package)
- Easy to mount with 1 screw (isolated mounting screw hole)
- Surface mountable, high power case style
- Reduces assembly time and cost
- High power density

Symbol	Test Conditions	Characteristic Values (T <sub>J</sub> = 25°C, unless otherwise specified)		
		min.	typ.	max.
BV <sub>CES</sub>	I <sub>C</sub> = 750 μA, V <sub>GE</sub> = 0 V	600		V
V <sub>GE(th)</sub>	I <sub>C</sub> = 2.5 mA, V <sub>CE</sub> = V <sub>GE</sub>	4		7 V
I <sub>CES</sub>	V <sub>CE</sub> = 0.8 • V <sub>CES</sub> V <sub>GE</sub> = 0 V			200 μA 3 mA
I <sub>GES</sub>	V <sub>CE</sub> = 0 V, V <sub>GE</sub> = ±20 V			±100 nA
V <sub>CE(sat)</sub>	V <sub>GE</sub> = 15 V			I <sub>C</sub> = I <sub>C90</sub> I <sub>C</sub> = I <sub>C25</sub> 2.0 V 2.7 V



Fig.1 Saturation Characteristics

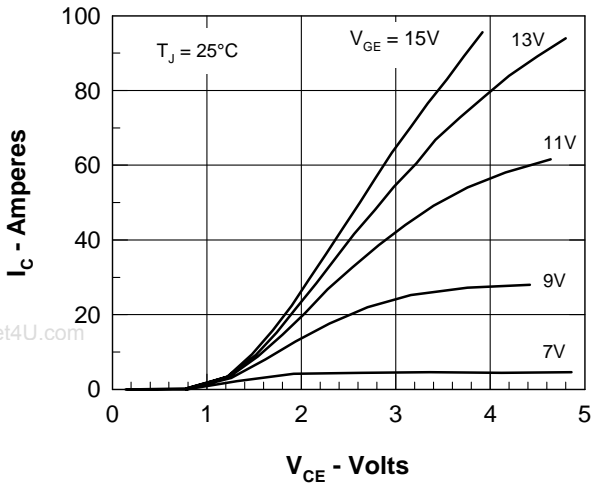


Fig.2 Output Characteristics

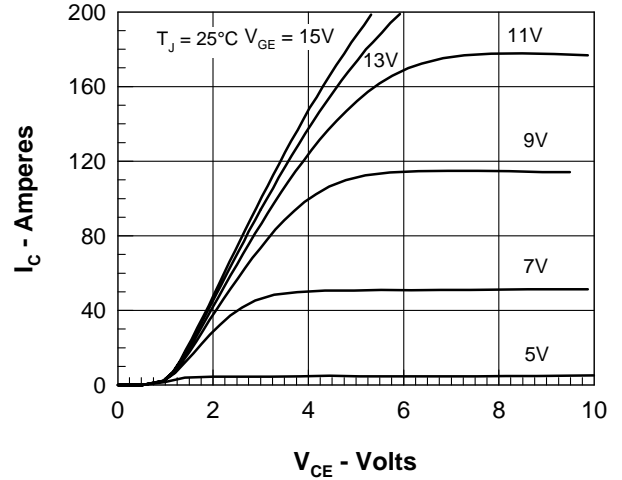


Fig.3 Collector-Emitter Voltage vs. Gate-Emitter Voltage

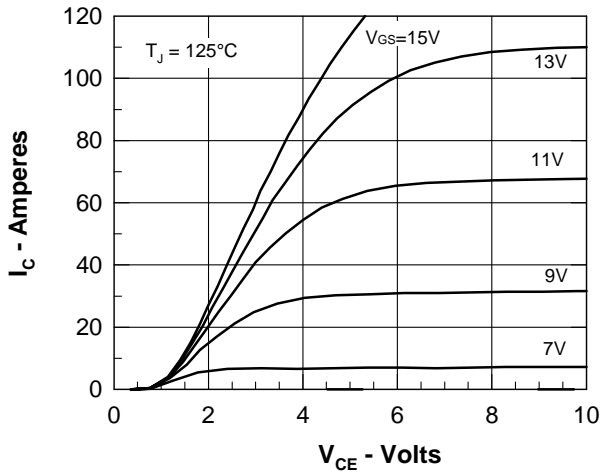


Fig.4 Temperature Dependence of Output Saturation Voltage

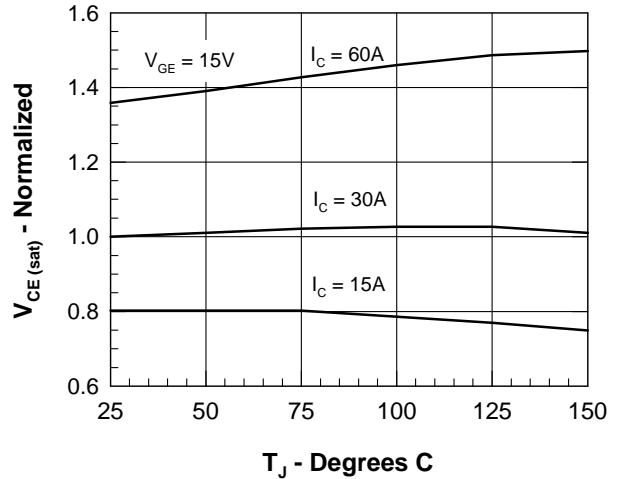


Fig.5 Input Admittance

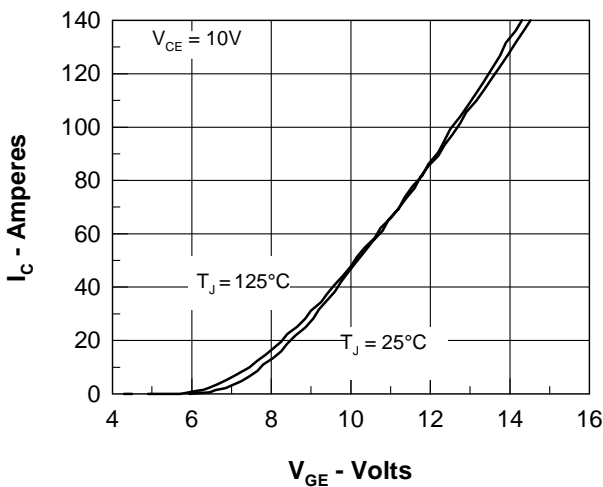


Fig.6 Temperature Dependence of Breakdown and Threshold Voltage

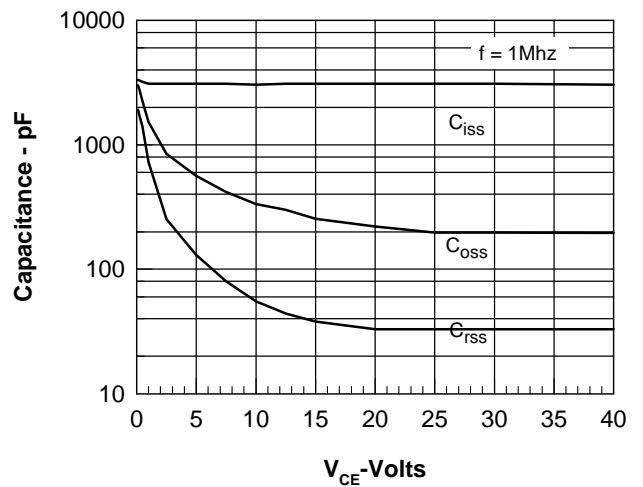


Fig.7 Turn-Off Energy per Pulse and Fall Time on Collector Current

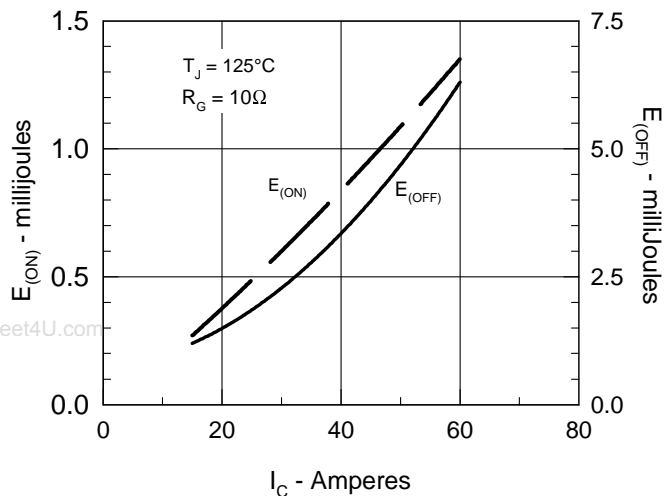
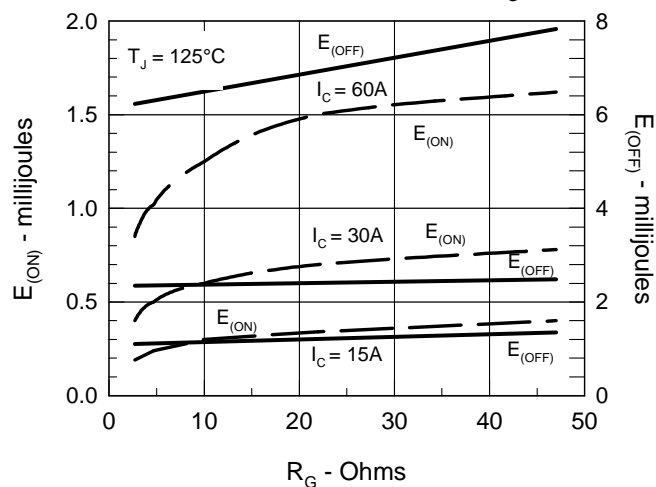

 Fig.8 Dependence of Turn-Off Energy Per Pulse and Fall Time on  $R_G$ 


Fig.9 Gate Charge Characteristic Curve

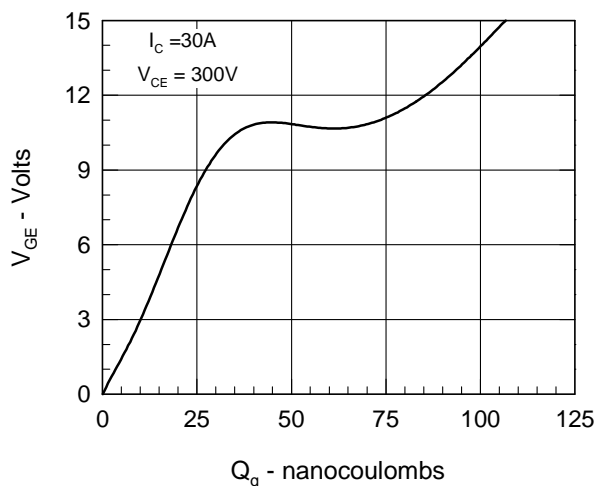


Fig.10 Turn-Off Safe Operating Area

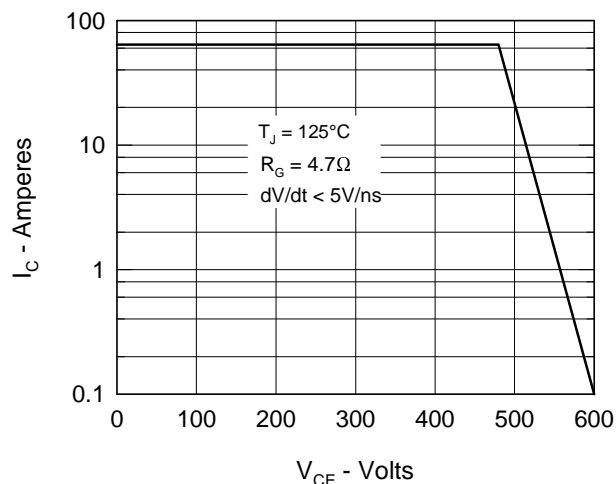
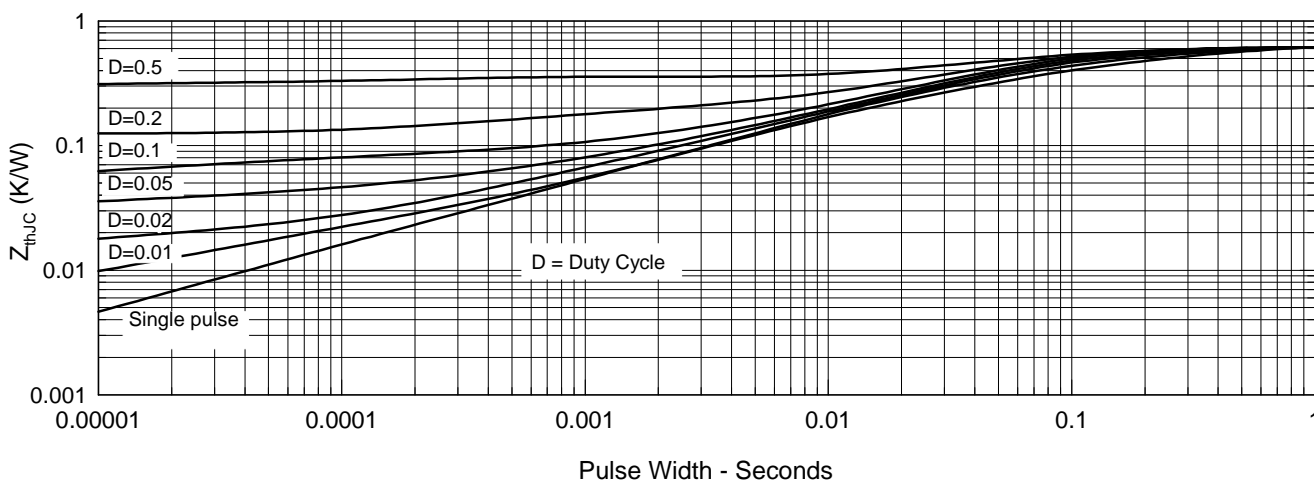


Fig.11 Transient Thermal Resistance



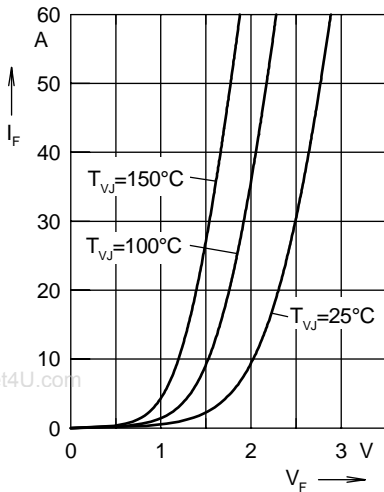


Fig. 12 Forward current  $I_F$  versus  $V_F$

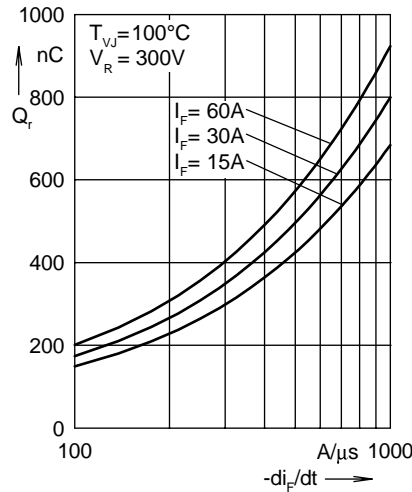


Fig. 13 Reverse recovery charge  $Q_r$  versus  $-di_F/dt$

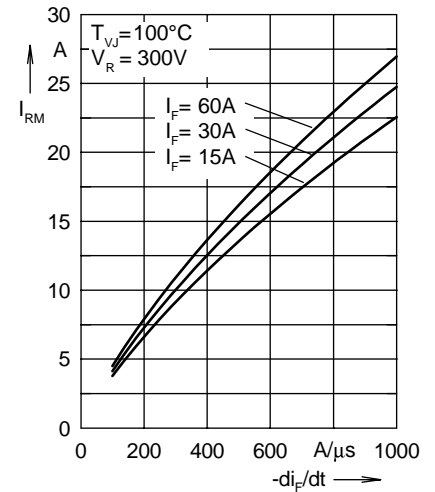


Fig. 14 Peak reverse current  $I_{RM}$  versus  $-di_F/dt$

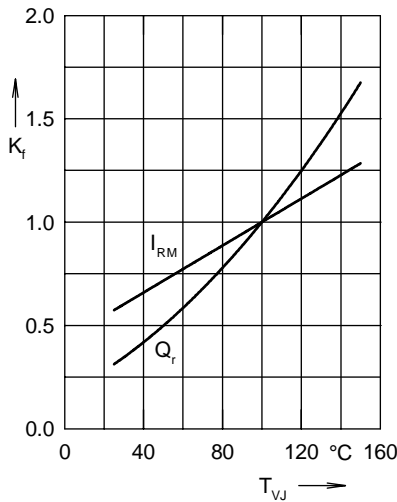


Fig. 15 Dynamic parameters  $Q_r$ ,  $I_{RM}$  versus  $T_{VJ}$

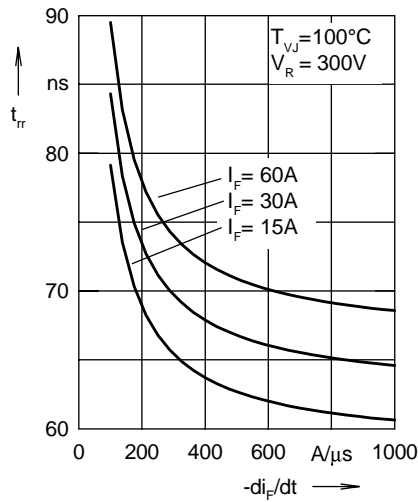


Fig. 16 Recovery time  $t_{rr}$  versus  $-di_F/dt$

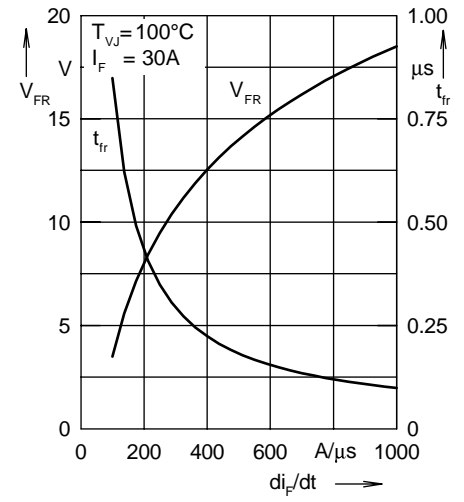


Fig. 17 Peak forward voltage  $V_{FR}$  and  $t_{fr}$  versus  $di_F/dt$

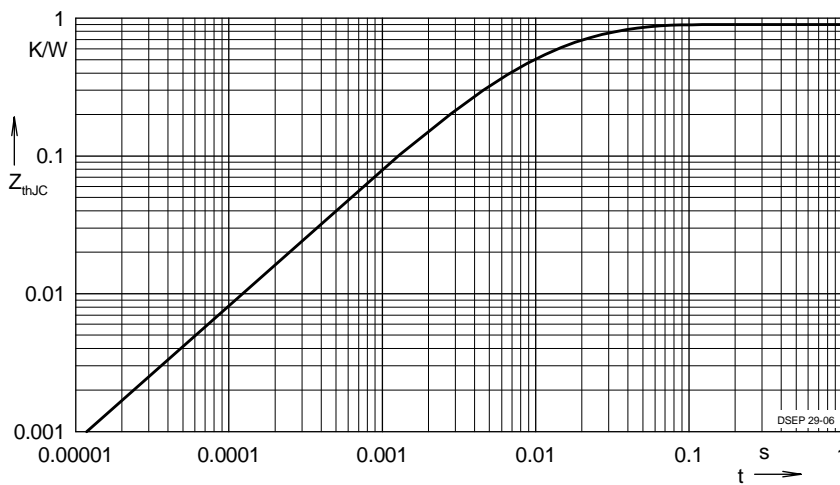


Fig. 18 Transient thermal resistance junction to case

Constants for  $Z_{thJC}$  calculation:

i	$R_{thi}$ (K/W)	$t_i$ (s)
1	0.502	0.0052
2	0.193	0.0003
3	0.205	0.0162